

Search Notes

Application/Control No.

10/564,108

Examiner

RIP A. LEE

Applicant(s)/Patent under
Reexamination

RAZAVI ET AL.

Art Unit

1796

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR